TOSHIBA MOS DIGITAL INTEGRATED CIRCUIT SILICON GATE CMOS

524,288-WORD BY 8-BIT CMOS STATIC RAM

DESCRIPTION

The TC55V8512J/FT is a 4,194,304-bit high-speed static random access memory (SRAM) organized as 524,288 words by 8 bits. Fabricated using CMOS technology and advanced circuit techniques to provide high speed, it operates from a single 3.3 V power supply. Chip enable ($\overline{\rm CE}$) can be used to place the device in a low-power mode, and output enable ($\overline{\rm OE}$) provides fast memory access. This device is well suited to cache memory applications where high-speed access and high-speed storage are required. All inputs and outputs are directly LVTTL compatible. The TC55V8512J/FT is available in plastic 36-pin SOJ and 44-pin TSOP with 400mil width for high density surface assembly.

FEATURES

- Fast access time (the following are maximum values)
 TC55V8512J/FT-12:12 ns
 TC55V8512J/FT-15:15 ns
- Low-power dissipation (the following are maximum values)

Cycle Time	12	15	20	25	ns
Operation (max)	170	140	130	110	mA

Standby:4 mA (both devices)

- Single power supply voltage of $3.3 \text{ V} \pm 0.3 \text{ V}$
- Fully static operation
- All inputs and outputs are LVTTL compatible
- Output buffer control using \overline{OE}
- Package:

SOJ36-P-400-1.27 (J) (Weight: 1.35 g typ) TSOP II44-P-400-0.80 (FT) (Weight: 0.45 g typ)

PIN ASSIGNMENT (TOP VIEW)

(TC55V8512J)

36 PIN SOJ 44 PIN TSOP

A17	10
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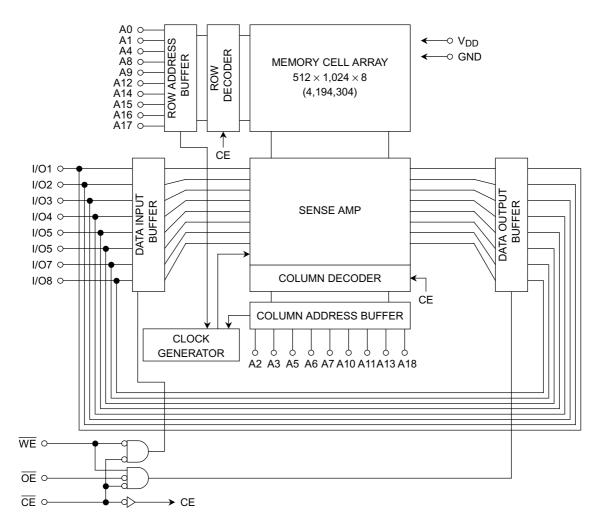
(TC55V8512FT)

PIN NAMES

A0 to A18	Address Inputs	
I/O1 to I/O8	Data Inputs/Outputs	
CE	Chip Enable Input	
WE	Write Enable Input	
ŌĒ	Output Enable Input	
V _{DD}	Power (+3.3 V)	
GND	Ground	
NC	No Connection	
NU	Not Usable (Input)	



BLOCK DIAGRAM



MAXIMUM RATINGS

SYMBOL	RATING	VALUE	UNIT
V_{DD}	Power Supply Voltage	-0.5 to 4.6	V
V _{IN}	Input Terminal Voltage	−0.5* to 4.6	V
V _{I/O}	Input/Output Terminal Voltage	−0.5* to V _{DD} + 0.5**	V
P_{D}	Power Dissipation	1.4	W
T _{solder}	Soldering Temperature (10s)	260	°C
T _{stg}	Storage Temperature	-65 to 150	°C
T _{opr}	Operating Temperature	-10 to 85	°C

^{*: -1.5} V with a pulse width of 20% t_{RC} min (4 ns max)

DC RECOMMENDED OPERATING CONDITIONS (Ta = 0° to 70°C)

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
V_{DD}	Power Supply Voltage	3.0	3.3	3.6	V
V _{IH}	Input High Voltage	2.0	_	V _{DD} + 0.3**	V
V _{IL}	Input Low Voltage	-0.3*	_	0.8	V

^{*: –1.0} V with a pulse width of 20% \cdot $t_{\mbox{\scriptsize RC}}$ min (4 ns max)

^{**:} V_{DD} + 1.5 V with a pulse width of 20% t_{RC} min (4 ns max)

^{**:} V_{DD} + 1.0 V with a pulse width of 20% t_{RC} min (4 ns max)



$\underline{DC\ CHARACTERISTICS}$ (Ta = 0° to 70°C, V_{DD} = 3.3 V \pm 0.3 V)

SYMBOL	PARAMETER	TEST CONDITION		MIN	TYP	MAX	UNIT
I _{IL}	Input Leakage Current (Except NU pin)	V _{IN} = 0 to V _{DD}		-1	_	1	μΑ
I _{LO}	Output Leakage Current	$\overline{CE} = V_{IH} \text{ or } \overline{WE} = V_{IL} \text{ or } \overline{OE} = V_{IH},$ $V_{OUT} = 0 \text{ to } V_{DD}$		-1	_	1	μΑ
I	Input Current	V _{IN} = 0 to 0.8 V		-1	_	20	
lı (NU)	(NU pin)	V _{IN} = 0 to 0.2 V		-1	_	1	μΑ
.,	Outside High Walliams	$I_{OH} = -2 \text{ mA}$ $I_{OH} = -100 \mu\text{A}$		2.4	_	_	
V _{OH}	Output High Voltage			V _{DD} – 0.2	_	_	V
.,	0.4	I _{OL} = 2 mA		_	_	0.4	V
V _{OL}	Output Low Voltage	I _{OL} = 100 μA		_	_	0.2	
			t _{cycle} = 12 ns	_	_	170	
	Out and the second	$\overline{CE} = V_{IL}, I_{OUT} = 0 \text{ mA},$	t _{cycle} = 15 ns	_	_	140	
I _{DDO}	Operating Current	$\overline{OE} = V_{IH},$ Other Input = V_{IH}/V_{II}	t _{cycle} = 20 ns	_	_	130	mA
- Curion		t _{cycle} =		_	_	110	
I _{DDS1}	Q	CE = V _{IH} , Other Input = V _{IH} or V _{IL}		_	_	50	
I _{DDS2}	Standby Current	$\overline{CE} = V_{DD} - 0.2 \text{ V}$, Other Input = $V_{DD} - 0.2 \text{ V}$	0.2 V or 0.2 V	_	_	4	mA

$\underline{\text{CAPACITANCE}} \text{ (Ta = 25°C, f = 1 .0 MHz)}$

SYMBOL	PARAMETER	TEST CONDITION	MAX	UNIT
C _{IN}	Input Capacitance	V _{IN} = GND	6	pF
C _{I/O}	Input/Output Capacitance	$V_{I/O} = GND$	8	pF

Note: This parameter is periodically sampled and is not 100% tested.

OPERATING MODE

MODE	CE	ŌĒ	WE	I/O1 to I/O8	POWER
Read	L	L	Н	Output	I _{DDO}
Write	L	*	L	Input	I _{DDO}
Outputs Disable	L	Н	Н	High Impedance	I _{DDO}
Standby	Н	*	*	High Impedance	I _{DDS}

^{* :} Don't care

Note: The NU pin must be left unconnected or tied to GND or a voltage level of less than 0.8 V. You must not apply a voltage of more than 0.8 V to the NU.



<u>AC CHARACTERISTICS</u> (Ta = 0° to 70°C $^{\text{(See Note 1)}}$, $V_{DD} = 3.3 \text{ V} \pm 0.3 \text{ V}$)

READ CYCLE

			TC55V8	512J/FT		
SYMBOL	PARAMETER	-1	12		15	UNIT
		MIN	MAX	MIN	MAX	
t _{RC}	Read Cycle Time	12	_	15	_	
t _{ACC}	Address Access Time	_	12	_	15	
t _{CO}	Chip Enable Access Time	_	12	_	15	
t _{OE}	Output Enable Access Time	_	6	_	8	
toH	Output Data Hold Time from Address Change	3	_	4	_	ns
t _{COE}	Output Enable Time from Chip Enable	3	_	4	_	
toee	Output Enable Time from Output Enable	1	_	1	_	
t _{COD}	Output Disable Time from Chip Enable	_	7	_	8	
t _{ODO}	Output Disable Time from Output Enable	_	7	_	8	

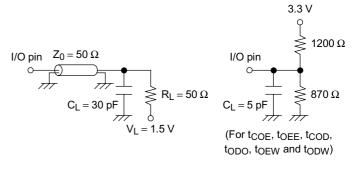
WRITE CYCLE

			TC55V8512J/FT				
SYMBOL	PARAMETER	-	12	-	15	UNIT	
		MIN	MAX	MIN	MAX	7	
t _{WC}	Write Cycle Time	12	_	15	_		
t _{WP}	Write Pulse Width	8	_	9	_		
t _{CW}	Chip Enable to End of Write	10	_	12	_		
t _{AW}	Address Valid to End of Write	10	_	12	_		
t _{AS}	Address Setup Time	0	_	0	_		
t _{WR}	Write Recovery Time	0	_	0	_	ns	
t _{DS}	Data Setup Time	7	_	8	_		
t _{DH}	Data Hold Time	0	_	0	_		
t _{OEW}	Output Enable Time from Write Enable	1	_	1	_		
t _{ODW}	Output Disable Time from Write Enable	_	7	_	8		

AC TEST CONDITIONS

PARAMETER	TEST CONDITION
Input Pulse Level	3.0 V/ 0.0 V
Input Pulse Rise and Fall Time	2 ns
Input Timing Measurement Reference Level	1.5 V
Output Timing Measurement Reference Level	1.5 V
Output Load	Fig.1

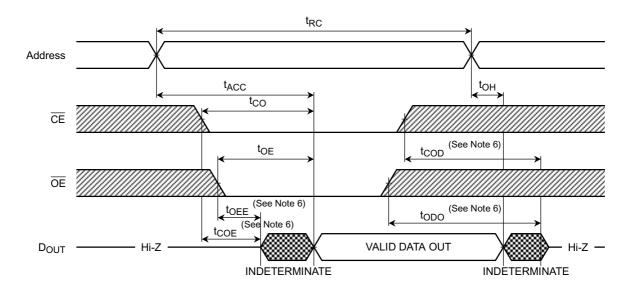
<u>Fig.1</u>



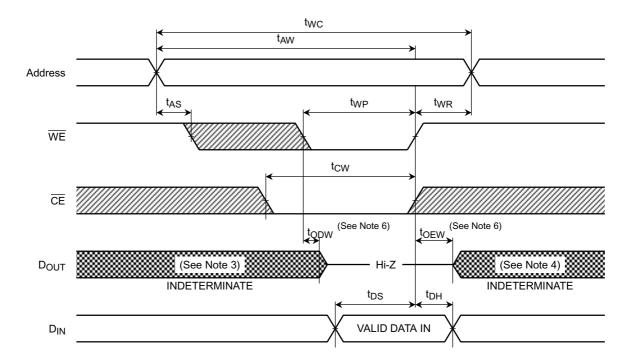


TIMING DIAGRAMS

READ CYCLE (See Note 2)

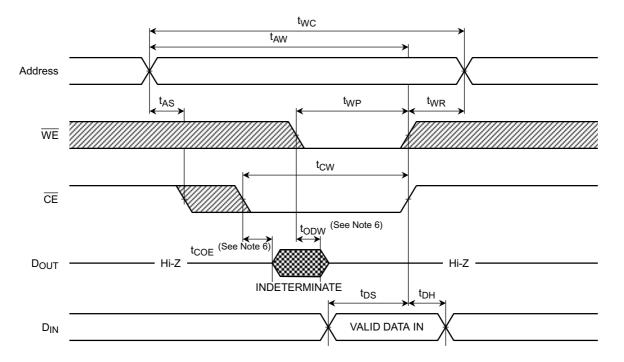


WRITE CYCLE 1 (WE CONTROLLED) (See Note 5)



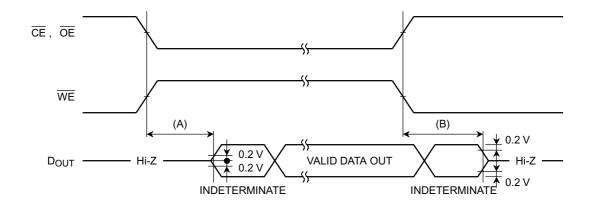


WRITE CYCLE 2 (CE CONTROLLED) (See Note 5)

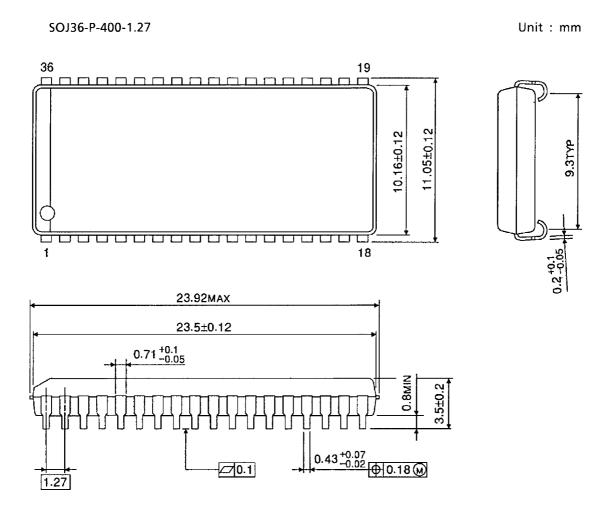


Note:

- (1) Operating temperature (Ta) is guaranteed for transverse air flow exceeding 400 linear feet per minute.
- (2) WE remains HIGH for the Read Cycle.
- (3) If $\overline{\text{CE}}$ goes LOW coincident with or after $\overline{\text{WE}}$ goes LOW, the outputs will remain at high impedance.
- (4) If $\overline{\text{CE}}$ goes HIGH coincident with or before $\overline{\text{WE}}$ goes HIGH, the outputs will remain at high impedance.
- (5) If \overline{OE} is HIGH during the write cycle, the outputs will remain at high impedance.
- (6) The parameters specified below are measured using the load shown in Fig.1.
 - (A) tCOE, tOEE, tOEW · · · · · Output Enable Time
 - (B) t_{COD} , t_{ODO} , t_{ODW} Output Disable Time

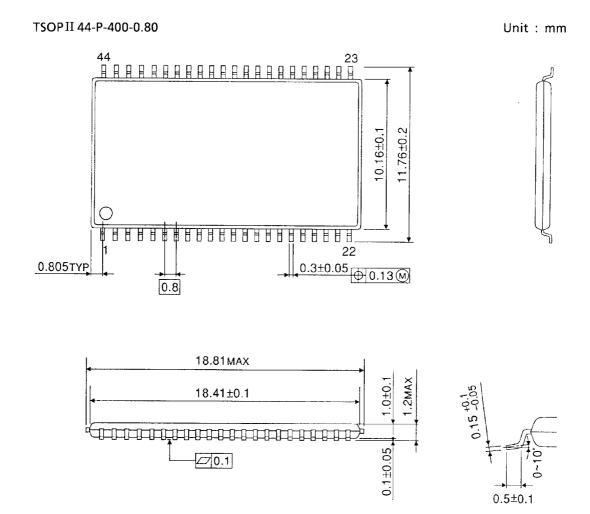


PACKAGE DIMENSIONS



Weight: 1.35 g (typ)

PACKAGE DIMENSIONS



Weight: 0.45 g (typ)

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